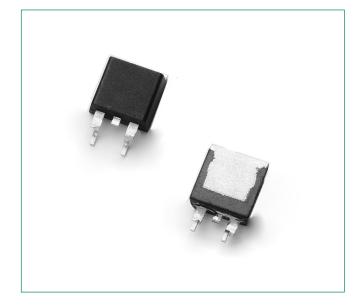
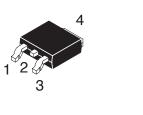


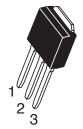
Surface Mount - 600V - 800V > MCR8DSM, MCR8DSN

MCR8DSM, MCR8DSN



Pin Out





Description

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

Po

Features

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and Holding Characteristics
- Available in Two Package Styles
 Surface Mount Lead Form Case 369C
 Miniature Plastic Package Straight Leads Case 369
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Human Body Model, 3B > 8000 V Machine Model, C > 400 V
- Pb-Free Packages are Available

Functional Diagram



Additional Information







Surface Mount - 600V - 800V > MCR8DSM, MCR8DSN

Maximum Ratings ($T_{J} = 25^{\circ}C$ unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) (– 40 to 1125°C, Sine Wave, 50 to 60 Hz, Gate Open) MCR8DSM MCR8DSN	V _{drm} , V _{rrm}	600 800	V
On-State RMS Current (All Conduction Angles; $T_c = 90^{\circ}C$)	I _{T (RMS)}	8.0	А
Average On–State Current (180° Conduction Angles; $T_c = 90$ °C)	I _{T(AV)}	5.1	А
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, TJ = 110°C)	I _{TSM}	60	A
Circuit Fusing Consideration (t = 8.3 ms)	l²t	34	A ² sec
Forward Peak Gate Power (Pulse Width \leq 10 $\mu sec, T_c$ = 90°C)	P _{GM}	5.0	W
Forward Average Gate Power (t = 8.3 msec, $T_c = 90^{\circ}C$)	P _{gm (AV)}	0.5	W
Forward Peak Gate Current (Pulse Width $\leq 1.0 \ \mu sec$, T _c = 90°C)	I _{GM}	2.0	А
Operating Junction Temperature Range	Tj	-40 to 110	°C
Storage Temperature Range	T _{stg}	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

Thermal Characteristics

Rating	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{sJC}	2.2	
Thermal Resistance, Junction-to-Ambient	R _{8JA}	88	°C/W
Thermal Resistance, Junction-to-Ambient (Note 2)	R _{8JA}	80	
Maximum Device Temperature for Soldering Purposes (Note 3)	TL	260	°C

Surface Mount - 600V - 800V > MCR8DSM, MCR8DSN

Electrical Characteristics \cdot **OFF** (T₁ = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Forward or Reverse Blocking Current (Note 3) (V_{AK} = Rated V_{DRM} or $V_{RRM'}$, R_{GK} = 1.0 k Ω	$T_{J} = 25^{\circ}C$	I _{drm} ,	-	-	10	uA
(NOTE 3) $(V_{AK} = 110100 V_{DRM} OT V_{RRM}, 11_{GK} = 1.0 K22$	T _J = 110°C	I _{RRM}	-	-	500	μΑ

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Reverse Gate Blocking Voltage ($I_{gR} = 10 \ \mu A$)		V _{grm}	10	12.5	18	V
Peak Reverse Gate Blocking Current ($V_{gR} = 10 \text{ V}$)		I _{rgm}	-	-	1.2	μA
Peak Forward On–State Voltage (Note 4) (I_{TM} = 16 A)		V _{TM}	_	1.4	1.8	V
AK L	Γ _J = 25°C) = −40°C)	I _{gt}	5.0 -	12 -	200 300	μΑ
(T _J	「」= 25°C) = −40°C) 」= 125°C)	V _{gt}	0.45 - 0.2	0.65 – –	1.0 1.5 –	V
	kΩ) T _J = 25°C) = -40°C)	I _H	0.5 –	1.0	6.0 10	mA
	T _J = 25°C) = -40°C)	I _L	0.5	1.0 _	6.0 10	mA
Total Turn–On Time (Source Voltage = 12 V, R _s = 6.0 kΩ, IT = 16 A(pk), R _{gK} = 1.0 kΩ) (Rated V _{DRM} , Rise Time = 20 ns, Pulse Width = 10 μs)	(VD =	tgt	_	2.0	5.0	μs

Dynamic Characteristics

Dynamic Characteristics					
Characteristic	Symbol	Min	Тур	Max	Unit
Critical Rate of Rise of Off–State Voltage ($V_D = 0.67 \text{ X}$ Rated V_{DRM} , Exponential Waveform, $R_{GK} = 1.0 \text{ k}\Omega$, $T_J = 110^{\circ}\text{C}$)	dv/dt	2.0	10	_	V/µs

^{2.} Surface mounted on minimum recommended pad size.

3. Ratings apply for negative gate voltage or RGK = 1.0 kQ. Devices shall not have a positive gate voltage concurrently with a negative voltage on the anode. Devices should not be tested with a constant current source for forward and reverse blocking capability such that the voltage applied exceeds the rated blocking voltage.

4. Pulse Test; Pulse Width \leq 2.0 msec, Duty Cycle \leq 2%.

5. RGK current not included in measurements.



Surface Mount – 600V - 800V > MCR8DSM, MCR8DSN

Voltage Current Characteristic of SCR

Symbol	Parameter
V _{drm}	Peak Repetitive Forward Off State Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Reverse Off State Voltage
I _{RRM}	Peak Reverse Blocking Current
V _{TM}	Maximum On State Voltage
I _H	Holding Current

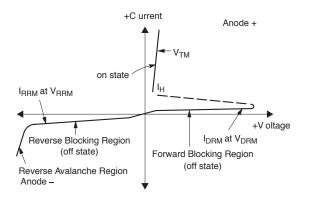
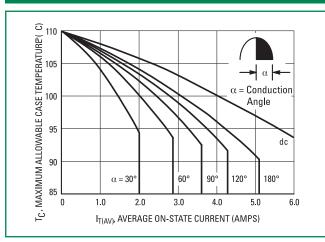




Figure 3. On–State Characteristics



$W_{T_{i}}^{100}$

Figure 2. On-State Power Dissipation

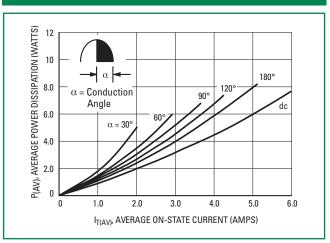
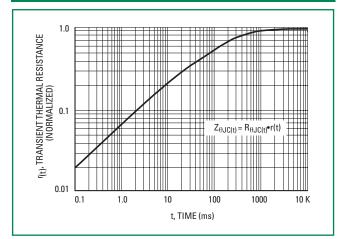


Figure 4. Transient Thermal Response





Surface Mount – 600V - 800V > MCR8DSM, MCR8DSN

Figure 5. Typical Gate Trigger Current vs Junction Temperature

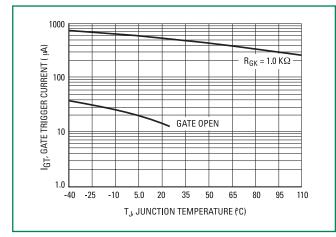


Figure 7. Typical Holding Current vs Junction Temperature

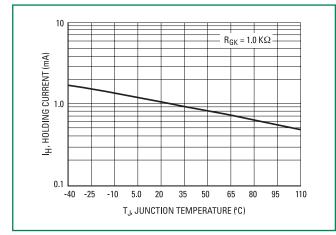


Figure 9. Holding Current versus Gate–Cathode Resistance

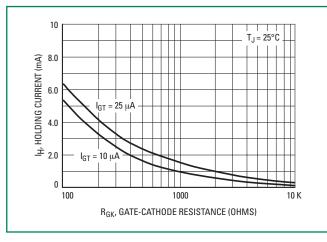


Figure 6. Typical Gate Trigger Voltage vs Junction Temperature

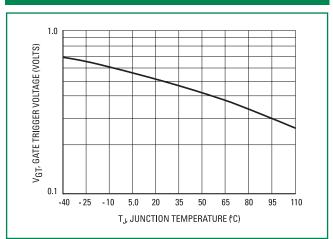


Figure 8. Typical Latching Current vs Junction Temperature

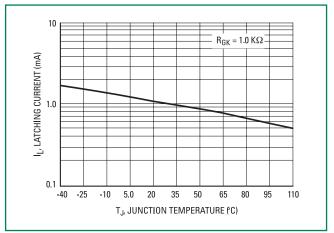
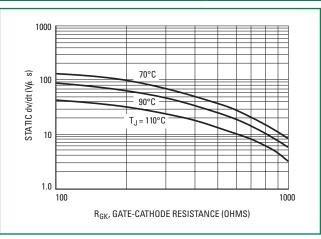


Figure 10. Exponential Static dv/dt vs Gate–Cathode Resistance and Junction Temperature





Surface Mount - 600V - 800V > MCR8DSM, MCR8DSN

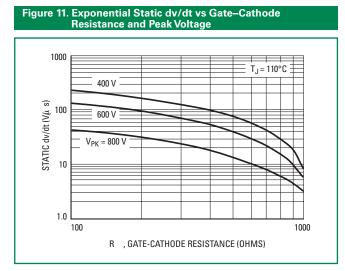
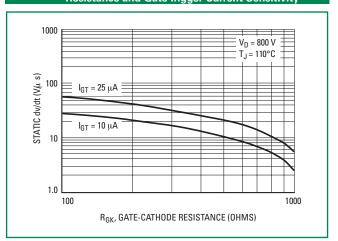


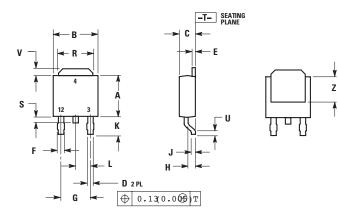
Figure 12. Exponential Static dv/dt vs Gate–Cathode Resistance and Gate Trigger Current Sensitivity





Surface Mount - 600V - 800V > MCR8DSM, MCR8DSN

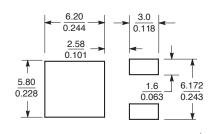
Dimensions



D.	Inches		Millim	eters	
Dim	Min	Max	Min	Max	
А	0.235	0.245	5.97	6.22	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
E	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.180	BSC	4.58	BSC	
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.102	0.114	2.60	2.89	
L	0.090	BSC	2.29	BSC	
R	0.180	0.215	4.57	5.45	
S	0.025	0.040	0.63	1.01	
U	0.020		0.51		
V	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: INCH.

Soldering Footprint



SCALE 3:1 (mm/inches)

Part Marking System



Y=	Year
WW =	Work Week
CR8DSx=	D evice Code
	x= M or N
G=	Pb–Free Package

Pin Assignment	
1	Cathode
2	Anode
3	Gate
4	Anode

Ordering Information

Device	Package	Shipping
MCR8DSMT4	DPAK	
MCR8DSMT4G	DPAK (Pb–Free)	2500/Tape & Reel
MCR8DSNT4	DPAK	
MCR8DSNT4G	DPAK (Pb–Free)	

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